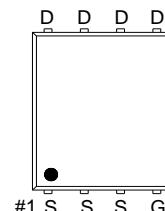
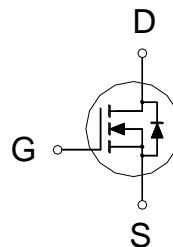


NIKO-SEM
**N-Channel Enhancement Mode
Field Effect Transistor**
P1410BK
PDFN 5x6P
Halogen-Free & Lead-Free
PRODUCT SUMMARY

$V_{(BR)DSS}$	$R_{DS(ON)}$	I_D
100V	14.5mΩ	42A

**ABSOLUTE MAXIMUM RATINGS ($T_A = 25^\circ\text{C}$ Unless Otherwise Noted)**

PARAMETERS/TEST CONDITIONS		SYMBOL	LIMITS	UNITS
Drain-Source Voltage		V_{DS}	100	V
Gate-Source Voltage		V_{GS}	± 20	V
Continuous Drain Current	$T_C = 25^\circ\text{C}$	I_D	42	A
	$T_C = 100^\circ\text{C}$		27	
Pulsed Drain Current ¹		I_{DM}	110	
Continuous Drain Current	$T_A = 25^\circ\text{C}$	I_D	12	
	$T_A = 70^\circ\text{C}$		9.8	
Avalanche Current		I_{AS}	21	
Avalanche Energy	$L = 1\text{mH}$	E_{AS}	224	mJ
Power Dissipation	$T_C = 25^\circ\text{C}$	P_D	60	W
	$T_C = 100^\circ\text{C}$		24	
Power Dissipation ³	$T_A = 25^\circ\text{C}$	P_D	5	W
	$T_A = 70^\circ\text{C}$		3.2	
Operating Junction & Storage Temperature Range		T_j, T_{stg}	-55 to 150	°C

THERMAL RESISTANCE RATINGS

THERMAL RESISTANCE		SYMBOL	TYPICAL	MAXIMUM	UNITS
Junction-to-Ambient ²	$t \leq 10\text{s}$	$R_{\theta JA}$	$^{\circ}\text{C} / \text{W}$	25	$^{\circ}\text{C} / \text{W}$
Junction-to-Ambient ²	Steady-State	$R_{\theta JA}$		50	
Junction-to-Case	Steady-State	$R_{\theta JC}$		2.1	

¹Pulse width limited by maximum junction temperature.²The value of $R_{\theta JA}$ is measured with the device mounted on 1in² FR-4 board with 2oz. Copper, in a still air environment with $T_A = 25^\circ\text{C}$.³The Power dissipation is based on $R_{\theta JA}$ $t \leq 10\text{s}$ value.

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ELECTRICAL CHARACTERISTICS (T_J = 25 °C, Unless Otherwise Noted)

PARAMETER	SYMBOL	TEST CONDITIONS	LIMITS			UNIT
			MIN	TYP	MAX	
STATIC						
Drain-Source Breakdown Voltage	V _{(BR)DSS}	V _{GS} = 0V, I _D = 250μA	100			V
Gate Threshold Voltage	V _{GS(th)}	V _{DS} = V _{GS} , I _D = 250μA	1.3	1.8	2.3	
Gate-Body Leakage	I _{GSS}	V _{DS} = 0V, V _{GS} = ±20V			±100	nA
Zero Gate Voltage Drain Current	I _{DSS}	V _{DS} = 80V, V _{GS} = 0V			1	
		V _{DS} = 80V, V _{GS} = 0V, T _J = 55 °C			10	μA
Drain-Source On-State Resistance ¹	R _{DS(ON)}	V _{GS} = 10V, I _D = 20A		11	14.5	
		V _{GS} = 4.5V, I _D = 15A		12	16	mΩ
Forward Transconductance ¹	g _{fs}	V _{DS} = 5V, I _D = 20A		50		S
DYNAMIC						
Input Capacitance	C _{iss}	V _{GS} = 0V, V _{DS} = 25V, f = 1MHz		4032		
Output Capacitance	C _{oss}			276		pF
Reverse Transfer Capacitance	C _{rss}			224		
Gate Resistance	R _g	V _{GS} = 0V, V _{DS} = 0V, f = 1MHz		0.67		Ω
Total Gate Charge ²	Q _g	V _{GS} = 10V		106		
		V _{GS} = 4.5V		56		
Gate-Source Charge ²	Q _{gs}	V _{DS} = 50V, V _{GS} = 10V, I _D = 20A		15		nC
Gate-Drain Charge ²	Q _{gd}			39		
Turn-On Delay Time ²	t _{d(on)}			25		
Rise Time ²	t _r			30		
Turn-Off Delay Time ²	t _{d(off)}	V _{DS} = 50V , I _D ≈ 20A, V _{GS} = 10V, R _{GEN} = 6Ω		132		nS
Fall Time ²	t _f			51		
SOURCE-DRAIN DIODE RATINGS AND CHARACTERISTICS (T_J = 25 °C)						
Continuous Current	I _S				50	A
Forward Voltage ¹	V _{SD}	I _F = 20A, V _{GS} = 0V			1.2	V
Reverse Recovery Time	t _{rr}	I _F = 20A, dI _F /dt = 100A / μS		40		nS
Reverse Recovery Charge	Q _{rr}			53		nC

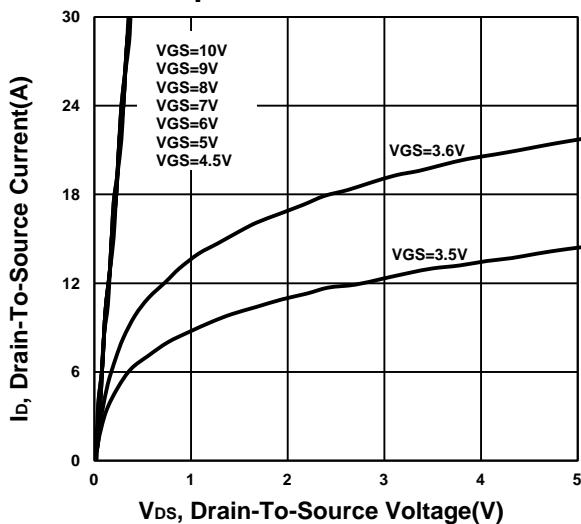
¹Pulse test : Pulse Width ≤ 300 μsec, Duty Cycle ≤ 2%.²Independent of operating temperature.

NIKO-SEM

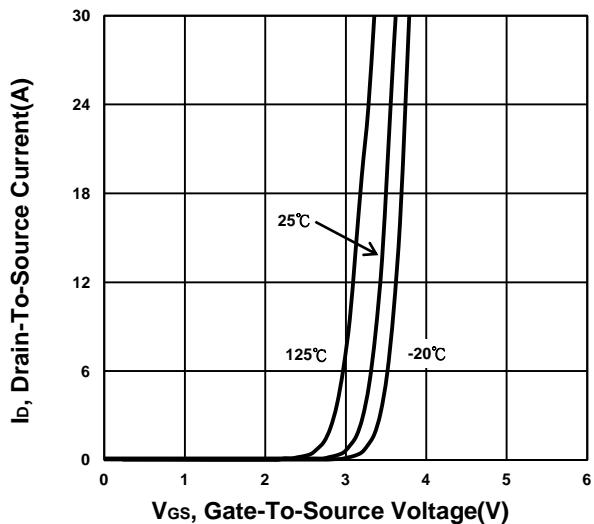
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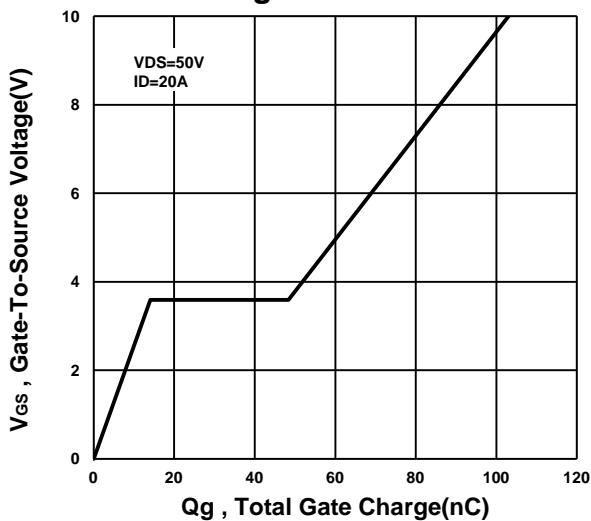
Output Characteristics



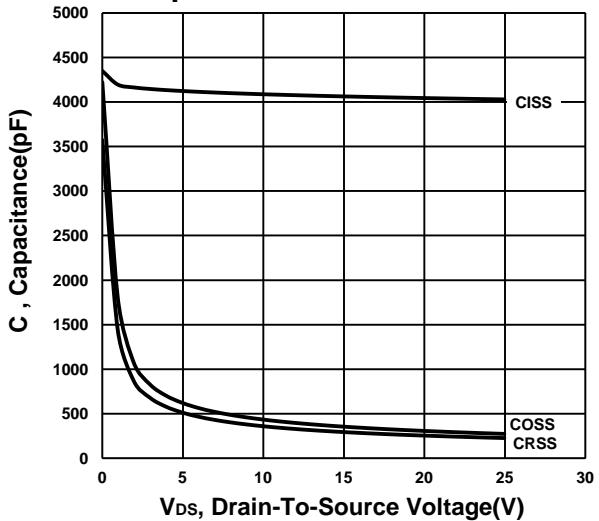
Transfer Characteristics



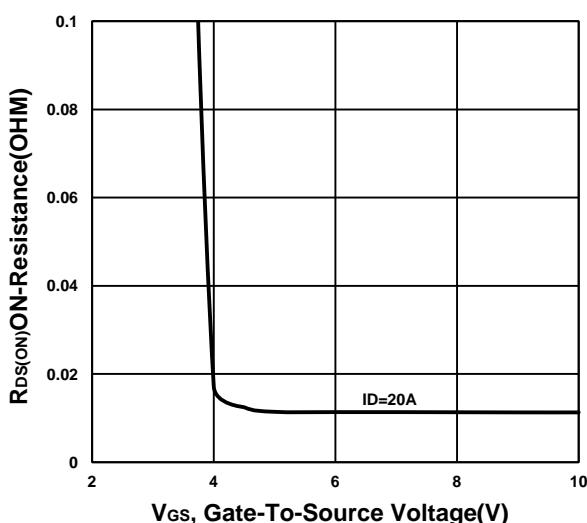
Gate charge Characteristics



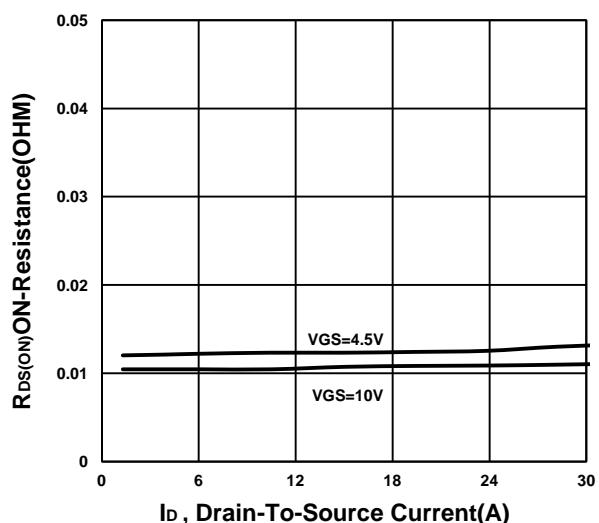
Capacitance Characteristic

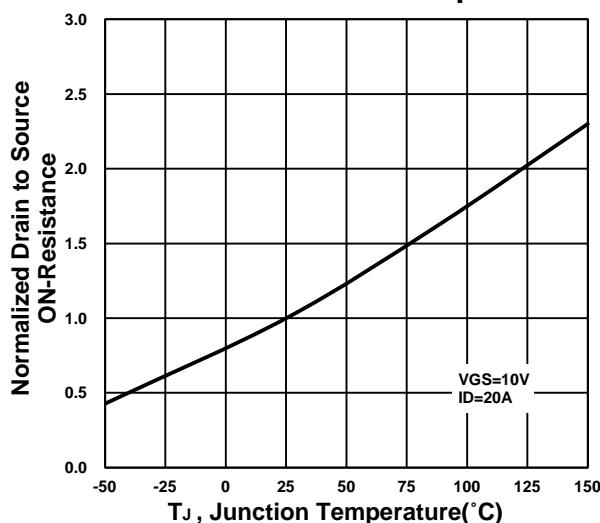
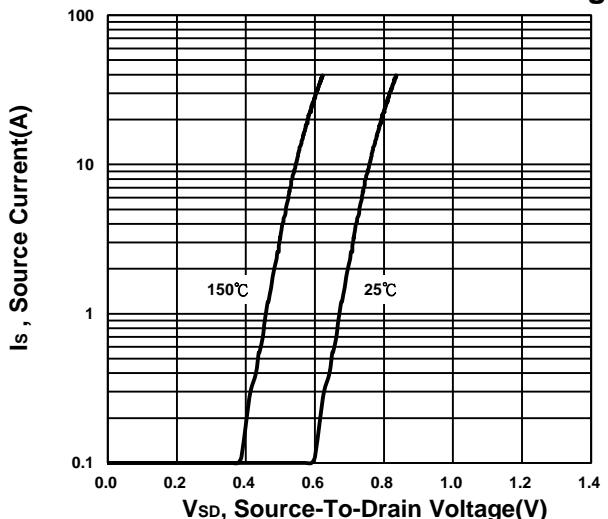
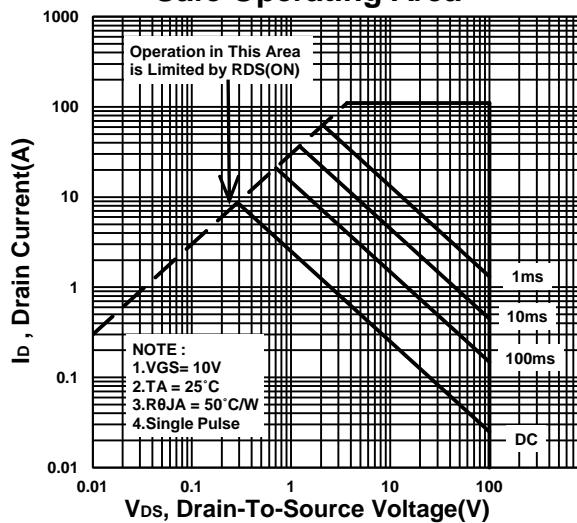
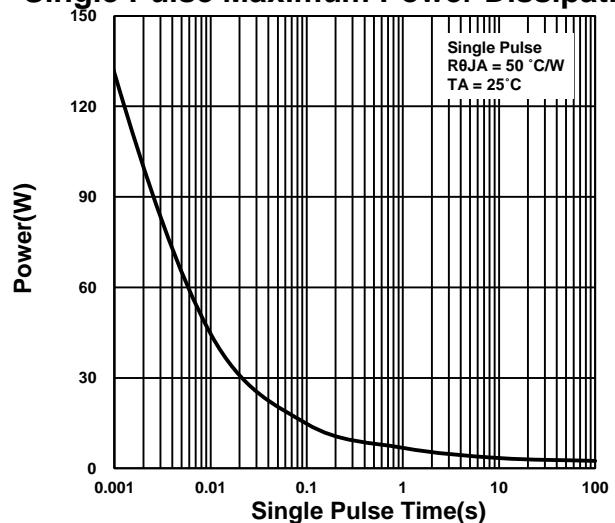


On-Resistance VS Gate-To-Source



On-Resistance VS Drain Current



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On-Resistance VS Temperature**Source-Drain Diode Forward Voltage****Safe Operating Area****Single Pulse Maximum Power Dissipation****Transient Thermal Response Curve**